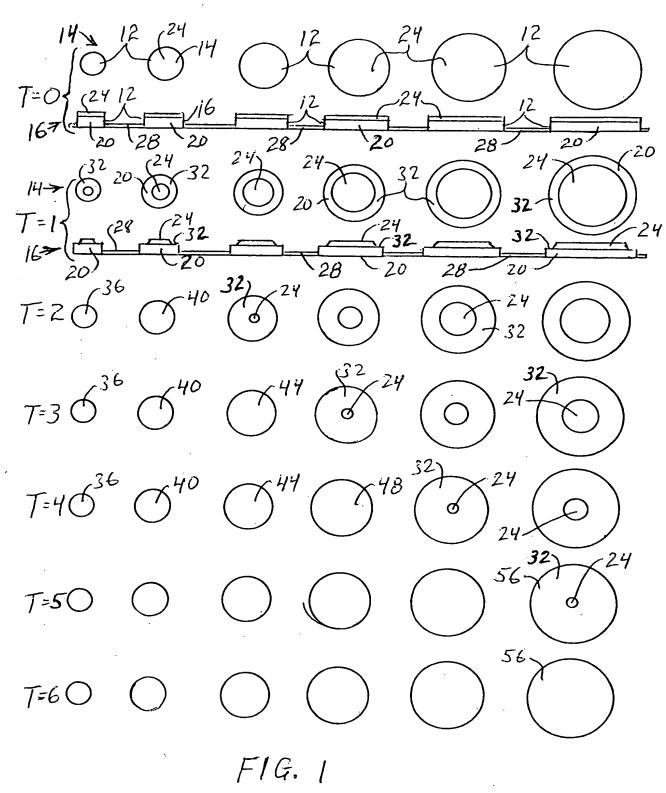
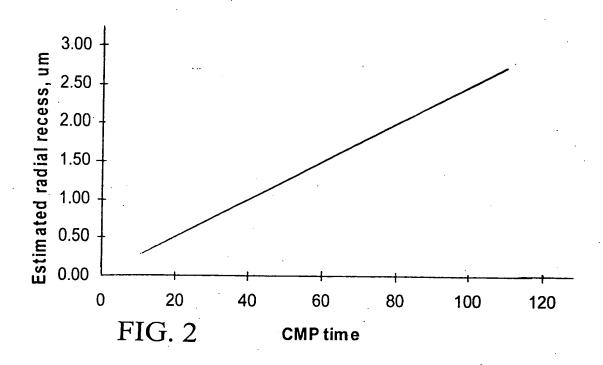
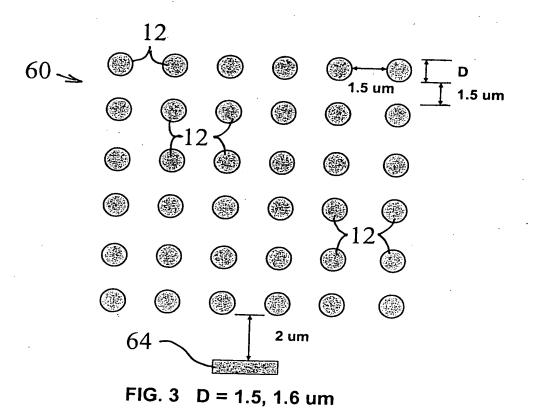
Hwu et al.

Dual Function Array Feature for CMP
Process Control and Inspection
S/N: New Application
Atty Docket #HSJ9-2003-0115US1



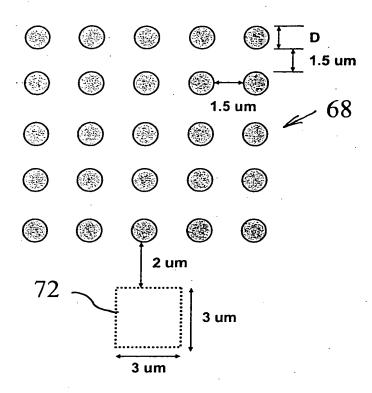
Hwu et al. Dual Function Array Feature for CMP Process Control and Inspection S/N: New Application
Atty Docket #HSJ9-2003-0115US1



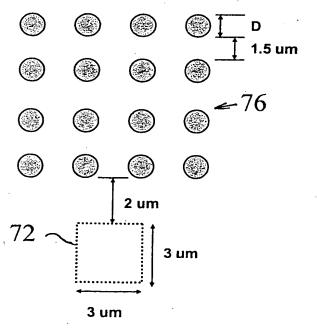


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D = 1.9, 2.2, 2.5 um. FIG. 4



D = 2.8, 3.1, 3.4 um. FIG. 5

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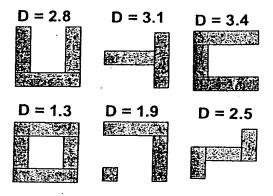


FIG. 6

